

**Notic of Referenc s Cited**

Application/Control No.

09/945,535

Applicant(s)/Patent Under  
Reexamination  
AHN ET AL.

Examiner

David S Blum

Art Unit

2813

Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-US006211035B1	04-2001	Moise et al	438/396
	B	US-4920071	04-1990	Thomas	438/585
	C	US-4647947	03-1987	Takeoka et al	346/135.1
	D	US-5,795,808	08-1998	Park	438/301
	E	US-4333808	06-1982	Bhattacharyya et al	204/192D
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)			
	U	Milton Ohring	THE MATERIALS SCIENCE OF THIN FILMS	Academic Press, Inc	1992 pages vi, 118, 121, 125
	V				
	W				
	X				

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.